Hybrid 8j325 Traveler

April 21, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J325 has die: 000-000 000-000 000-000 000-000 000-000 000-000 000-000 000-000

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j325 classification info. Created 11:14:56 04/21/00

Hybrid 8j325 quality: fair
Chip classification: fair fair fair good good good good good
Bad channels (chip-channel): 0-44
Bad cells: none
Random bad capacitors (chip-cell-channel): 1-1-104 1-1-105 1-10-103
   1-10-104 1-10-105 1-11-104 1-23-104 1-36-104 1-36-105 1-37-104 1-40-104
   1-40-105 1-41-104 1-43-104 1-43-105 1-45-104 1-45-105 2-13-5 2-15-5
   2-21-5 2-23-5 2-25-5 2-27-5 2-29-5 2-35-5 2-39-5 2-7-5
   2-8-5
Channels at pedestal needed for DCMS: 30.7 32.6 34.7 33.1 32.6 32.6 31.6 31.7
```

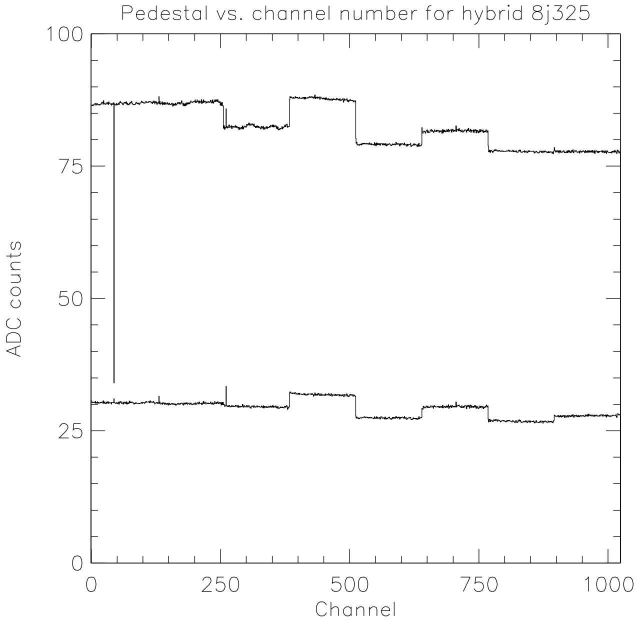
4 Comments

HV tested.

5 Pedestal

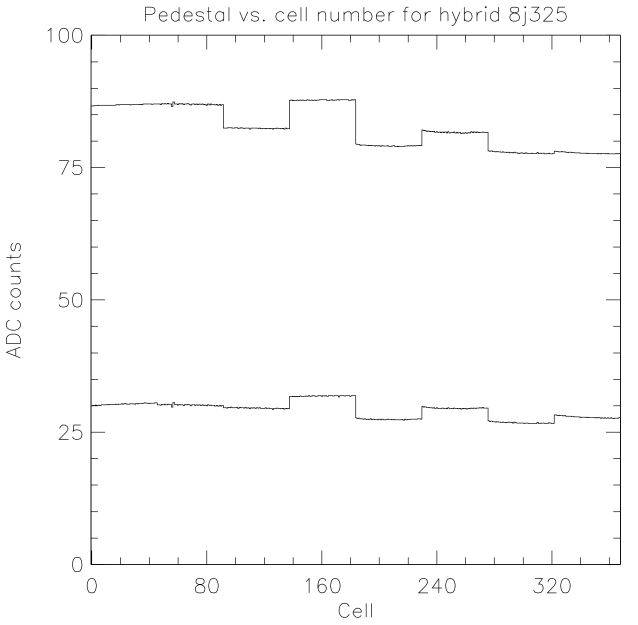
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

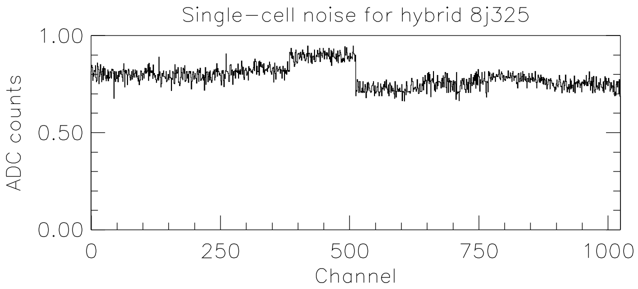
Pedestal vs. Pipeline Cell ID

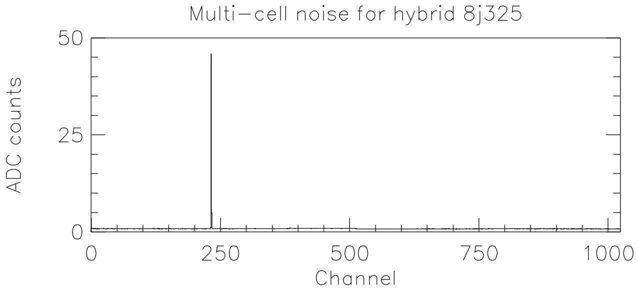


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

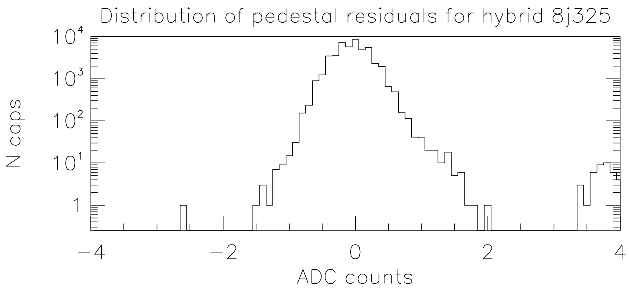
RMS Noise

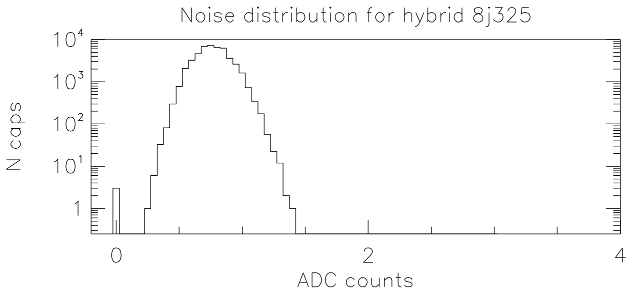




The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in